


<b>Search Notes</b>  	<b>Application/Control No.</b>  10599310	<b>Applicant(s)/Patent Under Reexamination</b>  VOLOSHIN ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
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SEARCH NOTES		
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text search strategy	9/29/2010	/YJK/
STN commercial Databases (Biosis, Medline, Embase, Embal, CAPlus) - see enclosed for text search strategy	9/29/2010	/YJK/

INTERFERENCE SEARCH			
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